

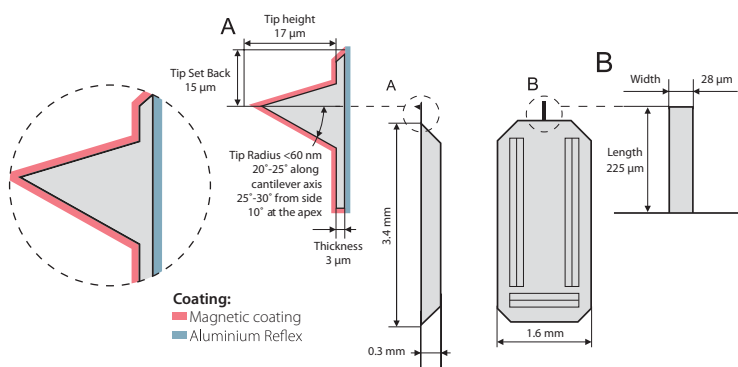


AFM probe Model: **MagneticMulti75-G**



This probe has alignment grooves on the backside of the holder chip.

- Magnetic Force Microscopy (MFM)
- Rotated Monolithic Silicon Probe
- Symmetric Tip Shape
- Chipsize: 3.4 x 1.6 x 0.3 mm
- Coating: Tip side - Magnetic, Detector side - Aluminium reflex
- This probe uses an “on scan angle” symmetric tip to provide a more symmetric representation of features over 200 nm.



	Typical Values	Range
Resonant Frequency	75 kHz	+/- 15 kHz
Force Constant	3 N/m	1 - 7 N/m
Cantilever Length	225 µm	+/- 10 µm
Mean Width	28 µm	+/- 5 µm
Thickness	3 µm	+/- 1 µm
Tip Height	17 µm	+/- 2 µm
Tip Set Back	15 µm	+/- 5 µm
Tip Radius	< 60 nm	
Coating	Tip side - Magnetic; Detector side - Aluminium	
Half Cone Angle	20° - 25° along cantilever axis 25° - 30° from side 10° at the apex	

Order Code	Units in Package	Coating	Price
Multi75M-G-10	10 pieces	Magnetic/Aluminium	\$240
Multi75M-G-50	50 pieces	Magnetic/Aluminium	\$1000